





SSD TEST EVOLUTION

(B/M Tool / Signal Integrity / Power Consumption)

Hynix Semiconductor Inc Flash Development Division 19th Oct. 2009



Contents

- Benchmark Tool
- Signal Integrity
- Power Consumption



Contents

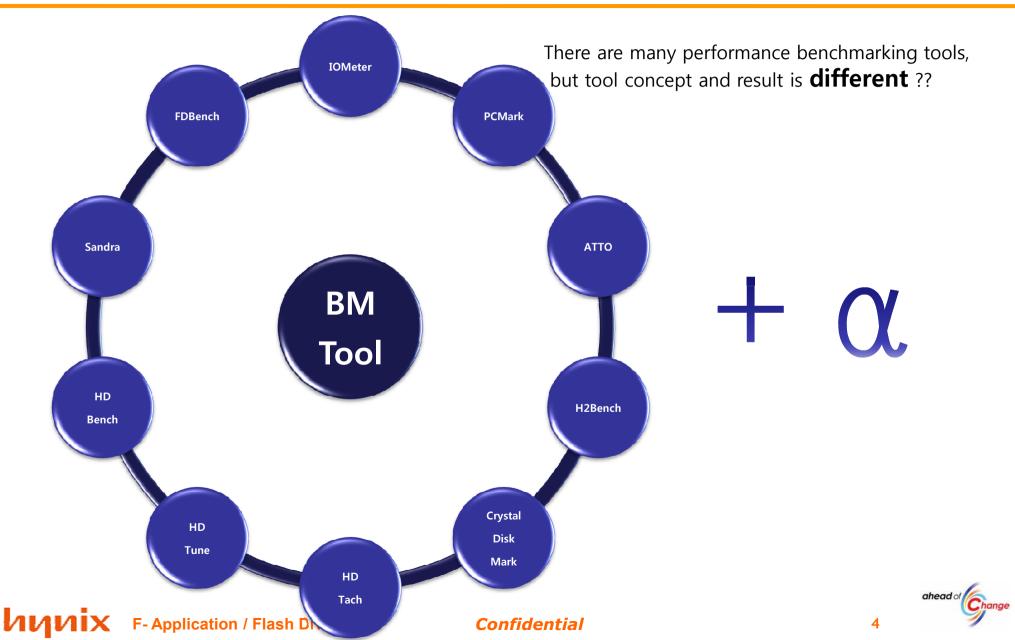
- Benchmark Tool
- Signal Integrity
- Power Consumption



Introduction of various BM Tools





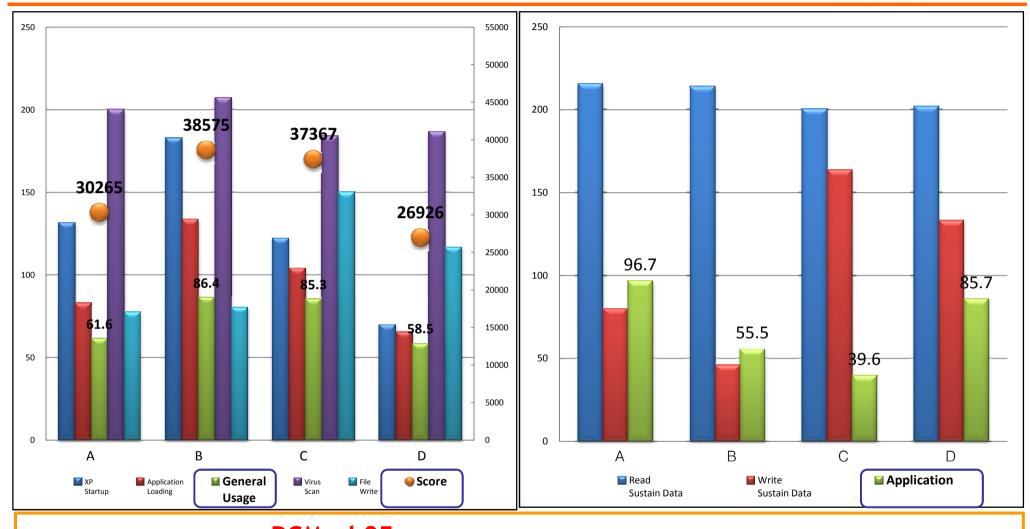


Example 1) PCMark 05 vs H2Bench Result





09/05.16~12/05.15



PCMark05 General Usage Score



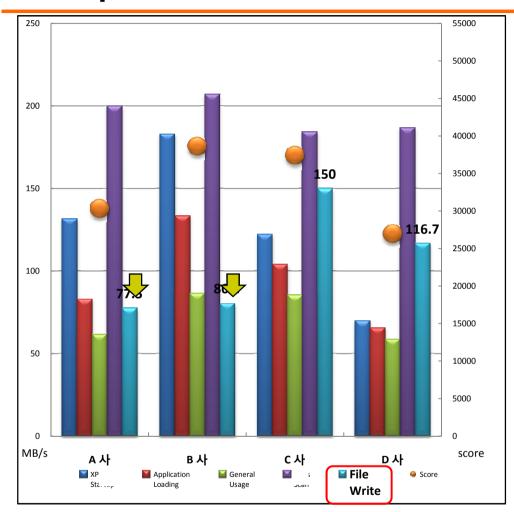
H2Bench Application

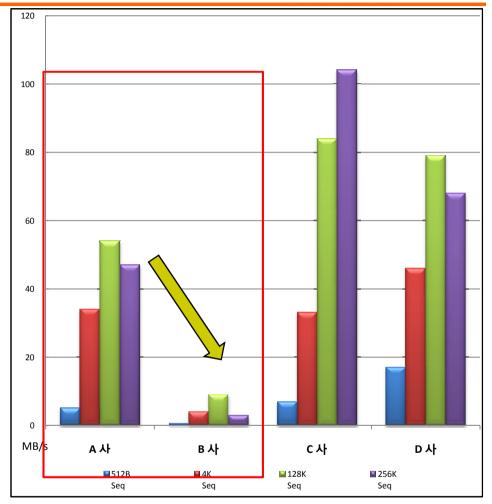
Example 2) PCMark 05 vs IOMeter 06 Result





09/05.16~12/05.15





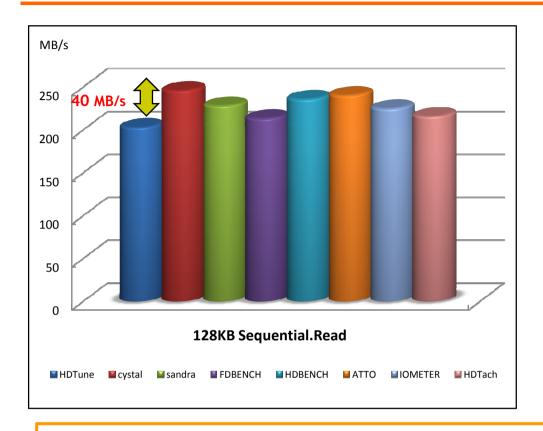
PCMark05 IOMeter06

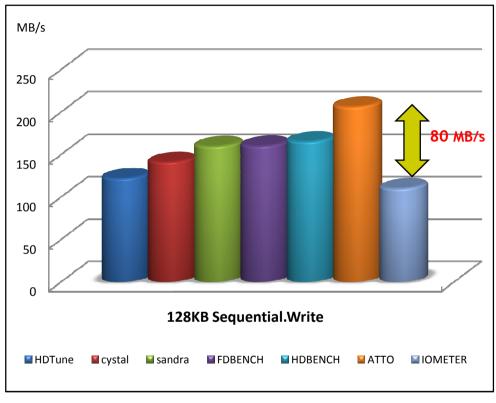
• It shows that both "A" and "B" are similar performance of disk operation for File Write in the PCMark05, but shows completely different results on the Sequential Write in the IOMeter 06. → Different result between PCMark05 and Iometer 06, even doing same operation.

Example 3) Performance Difference









- Shows different results among the various BM Tools.
- This chart shows 40MB-80MB/s performance difference based on many tools, even though we used the exactly same SSD sample and same conditions.



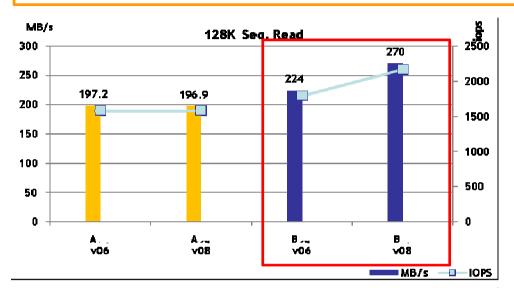
Example 4) Performance Difference @IOMeter

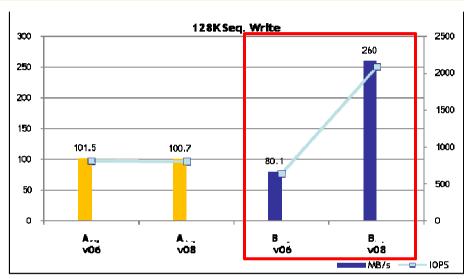


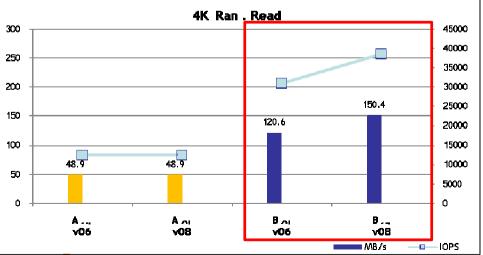


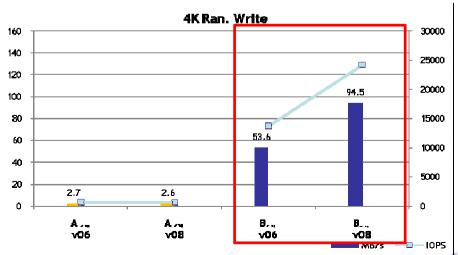
(Ingthe IOMeter) Change

- B company shows better performance in the IOMeter 2008 than IOMeter 2006.
- The two versions of IOMeter generate drastically different data patterns. → see APPENDIX









Analysis of various BM Tools





	IOMeter	PCMark	H2Bench	ATTO	HD Tach	HD Tune	Cystal diskMark	HDBench	Sandra	FDBENCH
Transfer Size	Variable	Fix (random)	Fix	Variable	Fix (64KB)	Fix (64KB)	Fix (seq. 128KB ran128/4KB)	Fix (seq. 128KB Ran 64KB)	Fix (128KB)	Fix (seq 128KB Ran 64KB)
DATA Pattern	06:RANDOM 08:2bit repetition	Almost ZERO pattern	Repetitive pattern	ALL ZERO		ALL ZERO	4bit repetition	Routine RANDOM Pattern	ALL ZERO	Routine RANDOM Pattern
CMD Read/Write	Read/write Seq/Ran	Read/Write Sea/Ran	Read./Write	Read/Write	Read Seq.	Read/Write Seq.	Read/Write Sea/Ran	Read/Write Sea/Ran	Read/Write Seq.	Read/Write Sea/Ran
OS	Windows Linux Netware	Windows	Windows (Win32 Console App)	Windows	Windows	Windows	Windows	Windows	Windows	Windows
Partition	physical/ Logical	logical	physical	logical	Physical/ logical	Physical/ Logical(read)	logical	logical	Physical/ Logical(read)	logical
Latency	V		V		V	V			V	
Multi process	V	V								
Queue Depth	V			V						
Precondition	V						e point and c			
CMD Duty cycle	V			No	t support s	pecific & crit	st Simple Rea tical option e of performa			
B.G.C	V				t give a larg	er perceptive	e or perioring	arrec		
Remark	*freezing *MB/s, IOPS	*Real home usage *Application test	*DATA Integrity check *application test			*detail graph			*detail graph *comparison with other SSD	* copy
іциі	F-Applic	ation / Flasl	n Div	Co	onfidential				9	ahead of Char



	PCMark05	PCMark Vantage
OS	Windows XP 32bit (SP2) Windows Vista 32bit	Windows Vista 전용
TEST ITEM (HDD Suite)	 XP startup Application Loading General Usage Virus scan File write 	 windows defender game HDD importing pictures Window Vista start-up Video editing Media center Adding music to Windows Media Player Application loading
SCORE	300 x (geomean of the HDD test suit results)	214.65 x (geomean of the HDD test suit results)

HDD Score = 300 * [geomean of the HDD test suite test results]

→300 * {(XP Startup * Application Loading * General Usage * Virus Scan * File Write)^1/5}



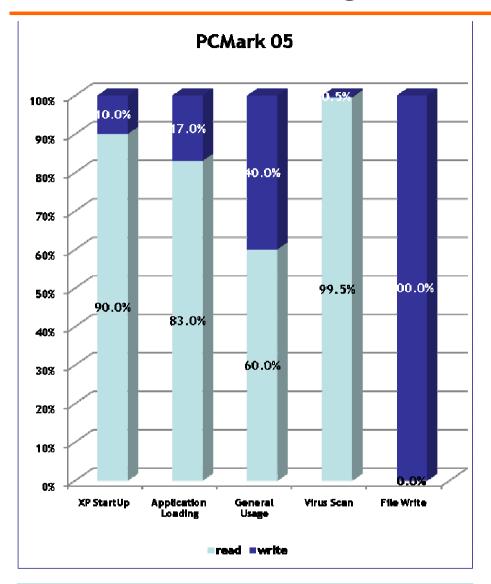


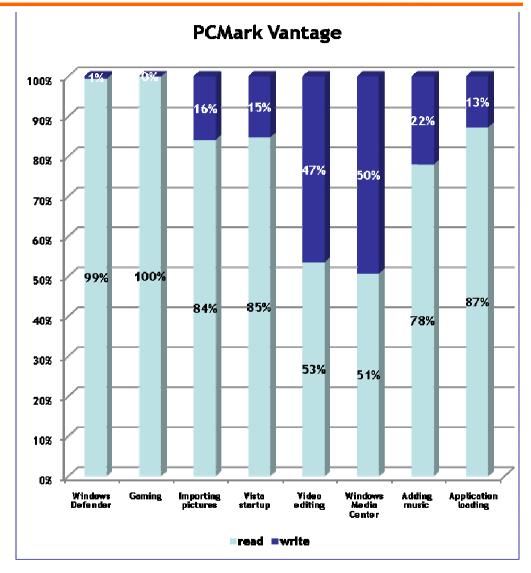
PCMark (05 & Vantage)





09/05.16~12/05.15





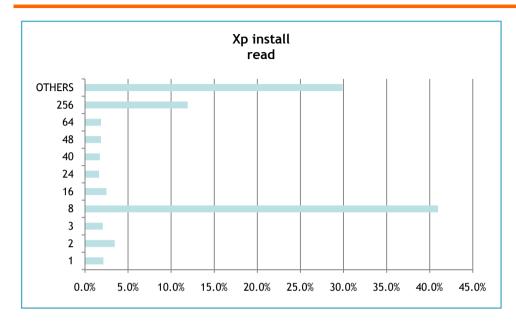
Total Ratio → 53% Read + 47% Write

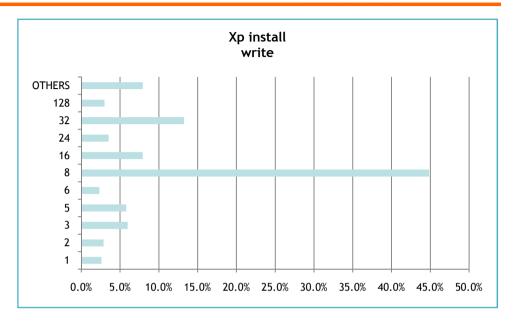
Total Ratio → 79.5% Read + 20.5% Write

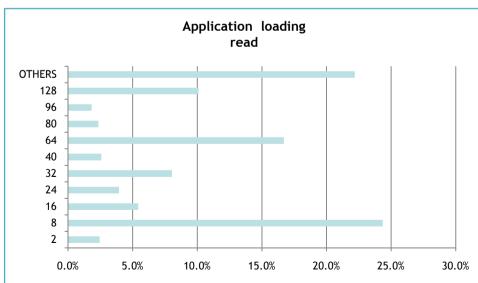


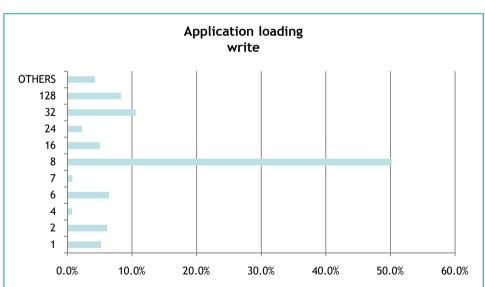














Hynix B/M Tool (Hi-Score)





Current Performance Measurement Issue

Various Performance B/M Tools

Introduction of Common BM Tools

Analyzation of BM Tools

What's Problem?

different results depending on which BM tool used or hardware.

What we need to do?

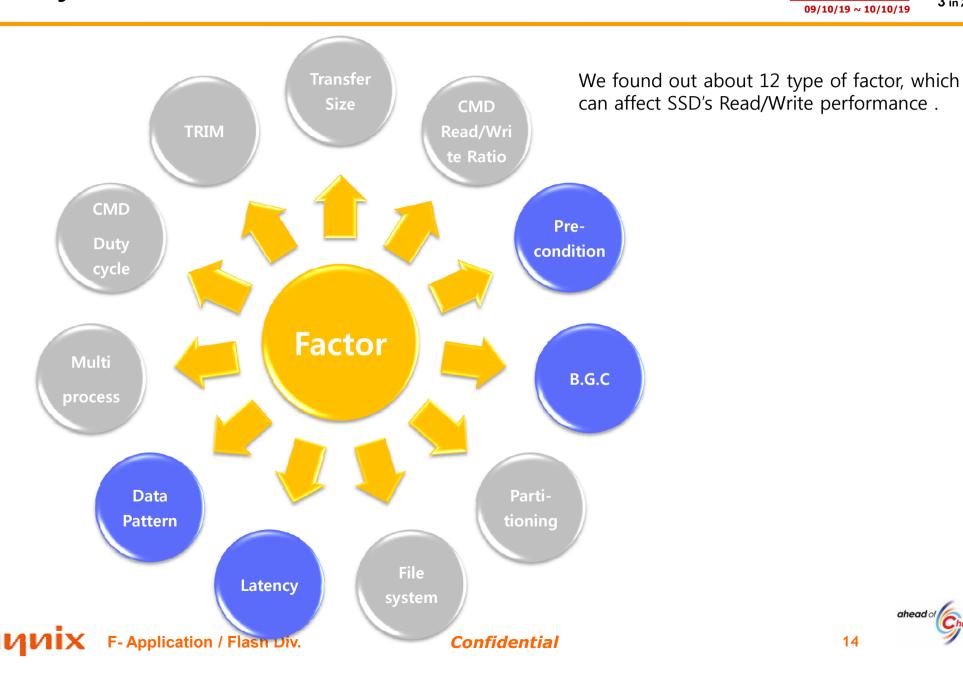
Standardization of Hardware and Software



Analysis of various BM Tools









What's the Problems?





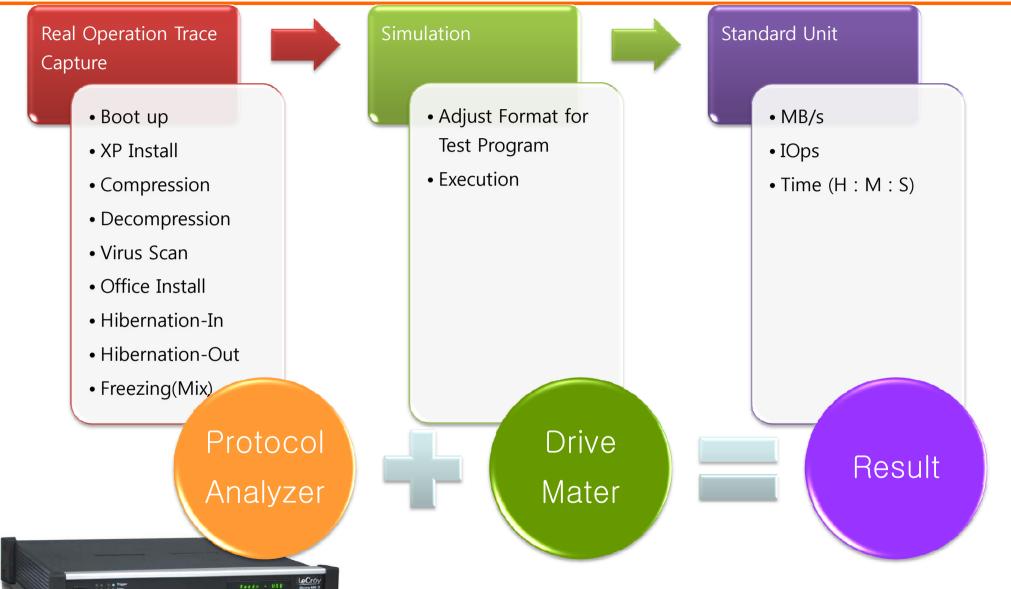
- I. Benchmarking tools show totally different results each others.
- II. In lack of consistency, reliability, objectivity for performance result.
- III. Need to standard regardless of test environment and features of the BM Tool.



Introduction of "HI-SCORE"

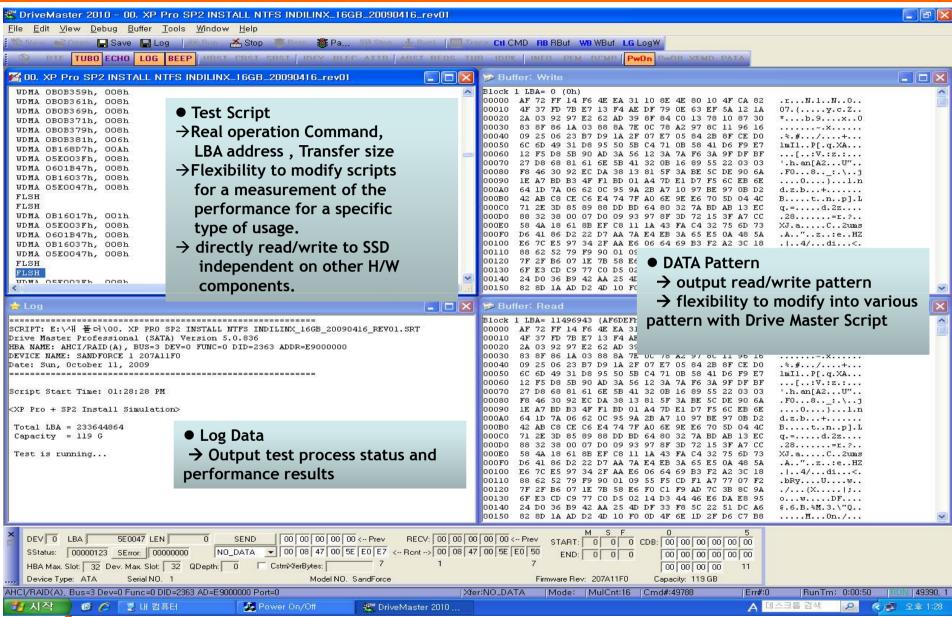








Introduction of "HI-SCORE"



Standardization of Benchmarking performance





Standardization of Hardware

• It is important for SSD performance measurement to be independent from hardware, especially CPU, RAM, Graphic, Motherboard.

Standardization of software

• Have to develop software including as various factors as possible to evaluate a broad perspective of performance.

HYNIX is developing our own optimized benchmarking index to achieve consistent result and accurate evaluation. We call that is "HiScore"





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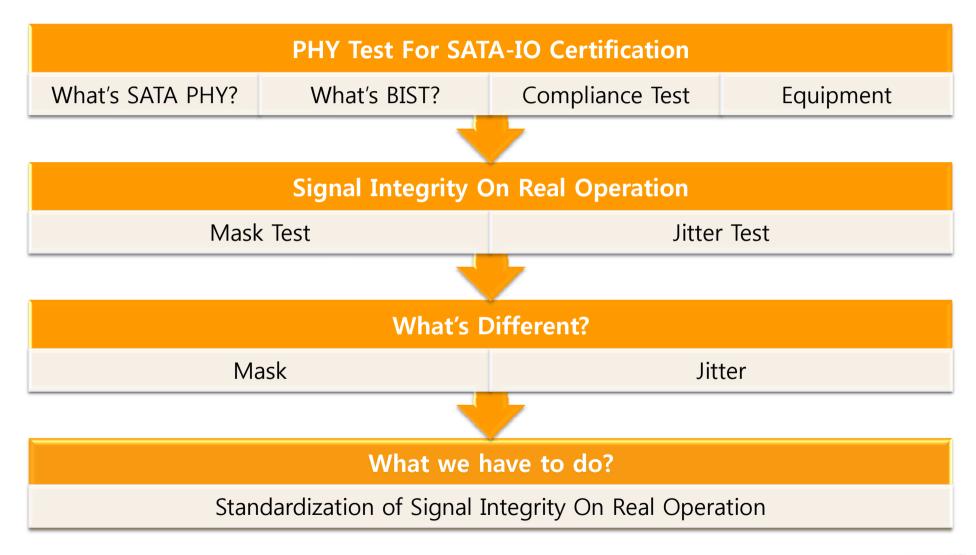
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Signal Integrity





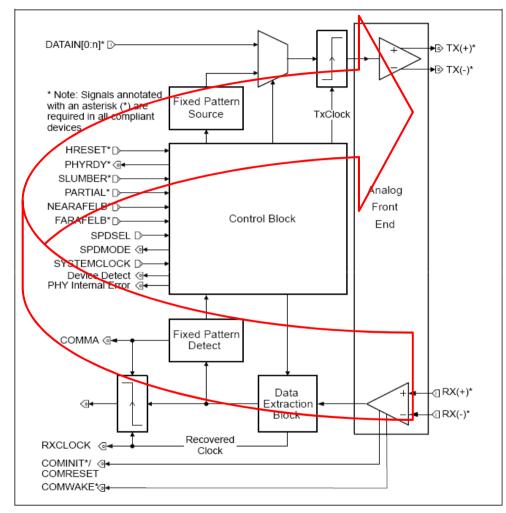




What is the SATA PHY?







Physical Plant Block Diagram

 The PHY layer is simply divided to a transmitter, Internal Interface, and a receiver.



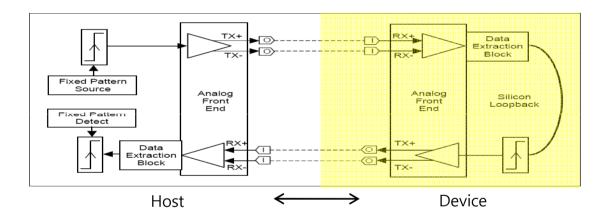
What is BIST?





1. BIST Mode

- 1. What is the BIST?
 - A Built-In Self-Test is a mechanism that permit a machine to test itself.
 - To verify an integrated circuit of internal feature.
 - Devices shall provide BIST-L mode for SATA Compliance Test.



- 2. BIST-L Mode (Far End Retimed Loopback Mode)
 - Data stream, at BIST-L mode, is extracted by the deserializer and data recovery circuit(DRC)
 - Data is being sent back through the Pattern Generator with appropriately inserted retiming ALIGNp primitives.
 - Provided data is decoded and descrambled.





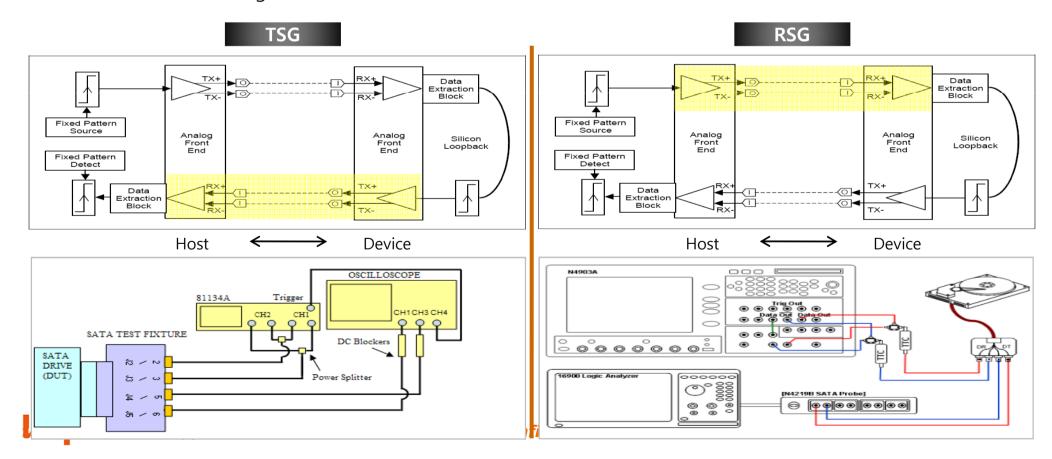


1. Transmitter Test

- PHY: Signal timing stability and SSC Analysis
- TSG: Rise/Fall Time, Transmitter AC parametric, Skew, Jitter, Amplitude
- OOB : Out of Band Signal Validation

2. Receiver Test (Jitter Tolerance Test)

- RSG: Receiver Jitter, Amplitude sensitivity compliance,
- RMT : RSG Margin test

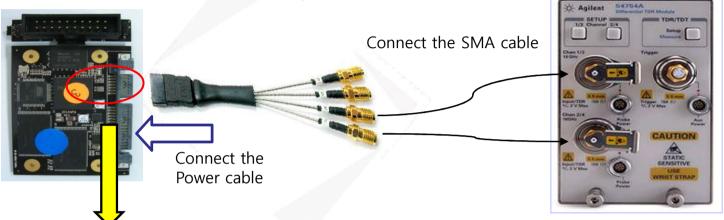






Channel Test (Impedance Test)

Rx/Tx: Device and Host electrical channel performance



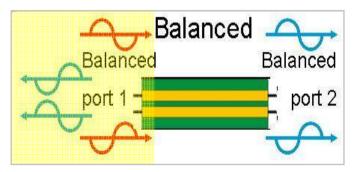
PHY

PACKGE

PCB

CONNECTOR

Test area may be divided four province



- SDD11 (Differential Return Loss): The magnitude measure of the differential mode reflection given differential mode excitation on each port.
- SCC11 (Common mode Return Loss): The magnitude measure of the common mode reflection given a common mode excitation on each port.
- SDC11 (Impedance Balance): The magnitude measure of the differential mode deflection given a common mode excitation on each port.

Note

- * Naming Convention : $S_{(mode\ response,\ mode\ stimulate)(port\ response,\ port\ stimulate)}$ 1) Mode Differential mode : DD / Common mode : CC / Mode Conversion : CD, DC
- 2) Port Reflection(Impedance): 11, 22 / Crosstalk(Cable test): 12, 21

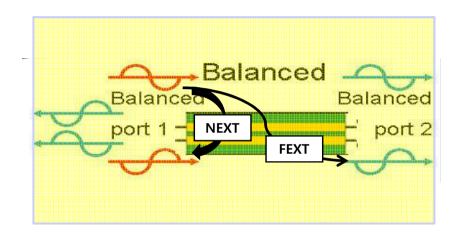






4. SI Test (Standard Internal Cable Test)

• SI Test: Cable Crosstalk, skew & frequency domain measurements



- NEXT (Near –End Crosstalk)
 - NEXT is interference between two pairs of a cable measured at the same end the cable the transmitter.
- FEXT (Far-End Crosstalk)
 - FEXT is interference between two pairs of a cable measured at the other end of the cable from the transmitter.
- The occurrence of any type of crosstalk can lead to communication issues such as loss of signal and transformation of frequency
- It's possible to improve if it is using shielded conductor on transfer path.







5. Test Items (Based on SATA 2.6 Specification)

SATA Gen1, Gen2 PHY/TSG/OOB Transmitter Testing	SA
PHY-01 Unit Interval	RS
PHY-02 Frequency Long Term Stability	RS
PHY-03 Spread-Spectrum Modulation Frequency	SA
PHY-04 Spread-Spectrum Modulation Deviation	TX
TSG-01 Differential Output Voltage	TX
TSG-02 Rise/Fall Time	TX
TSG-03 Differential Skew	12 TX
TSG-04 AC Common Mode Voltage	TX
TSG-05 Rise/Fall Imbalance	RX
TSG-06 Amplitude Imbalance	RX
TSG-07 TJ at Connector, Clock to Data, Fbaud/10	RX
TSG-08 DJ at Connector, Clock to Data, Fbaud/10	RX
TSG-09 TJ at Connector, Clock to Data, Fbaud/500 (Gen1)	RX
TSG-10 DJ at Connector, Clock to Data, Fbaud/500 (Gen1)	RX
TSG-11 TJ at Connector, Clock to Data, Fbaud/500 (Gen2)	SA
TSG-12 DJ at Connector, Clock to Data, Fbaud/500 (Gen2)	SI-
OOB-01 OOB Signal Detection Threshold	SI-
OOB-02 UI During OOB Signaling	SI-
OOB-03 COMINIT/RESET and COMWAKE Transmit Burst Length	SI-
OOB-04 COMINIT/RESET Transmit Gap Length	SI-
OOB-05 COMWAKE Transmit Gap Length	SI-
OOB-06 COMWAKE Gap Detection Windows	SI
OOB-07 COMINIT Gap Detection Windows	SI-

SATA RSG/RMT Receiver Testing
RSG-01 Gen1 (1.5Gb/s) Receiver Jitter Test
RSG-02 Gen2 (3.0Gb/s) Receiver Jitter Test
SATA Gen1, Gen2 Rx/Tx Channel Testing
TX-01 Pair Differential Impedance
TX-02 Single Ended Impedance (Informative)
TX-03 Gen2 (3Gb/s) Differential Mode Return Loss
TX-04 Gen2 (3Gb/s) Common Mode Return Loss
TX-05 Gen2 (3Gb/s) Impedance Balance
TX-06 Gen1 (1.5Gb/s) Differential Mode Return Loss
RX-01 Pair Differential Impedance
RX-02 Single Ended Impedance (Informative)
RX-03 Gen2 (3Gb/s) Differential Mode Return Loss
RX-04 Gen2 (3Gb/s) Common Mode Return Loss
RX-05 Gen2 (3Gb/s) Impedance Balance
RX-06 Gen1 (1.5Gb/s) Differential Mode Return Loss
SATA SI Testing
SI-01 Mated Connector Impedance
SI-02 Cable Absolute Differential Impedance
SI-03 Cable Pair Matching
SI-04 Common Mode Impedance
SI-05 Differential Rise Time
SI-06 Intra-pair Skew
SI-07 Insertion Loss
SI-08 Differential to Differential Crosstalk: NEXT
SI-09 Inter Symbol Interference



Compliance Test Result





6. Compliance Test Result

Test result summary		
Shows the test results as an overview		
blows die cesc resulcs as an overview		
Product Number:	SATA	
Serial Number:		
Description:		
User Name:	Unknown User	
User's Comment:		
Software Versions:		TV A see like de leste a leste
ValiFrame	1.14.20090211	TX Amplitude Imbalance
Sequencer	1.00.20090211	
Instrument Manager	1.00.20090211	
Serial Bus Family	1.00.20090211	
Excel Graph Table Viewer	1.00.20090211	
SATA	1.14.20090211	
_		
Test name	Result	TX Rise Time, 3.0 Gbps
JBERT MaxSJ Cal	Passed	
Diff Voltage Calibration	Passed	
Random Jitter Calibration	Passed	
Sinusoidal Jitter Calibration	Passed	
Tx Channel Speed_3G	Passed	
Tx Rise Time 3G	Passed	
Tx Fall Time 3G	Passed	
Tx Diff Skew HFTP	Passed	
Tx Rise Fall Imbal HFTP	Passed	
Tx TJ Fb500 HFTP	Passed	
Tx DJ Fb500 HFTP		
	Passed	
Tx Min Diff Voltage_3G	Passed	
Tx AmplitudeImbalance	Passed	
Tx Diff Skew MFTP	Passed	
Tx Rise Fall Imbal MFTP	Passed P	TX Fall Time, 3.0 Gbps
Tx AC Com Mode Voltage	Passed	TXT all Tille, 0.0 dbp3
Tx TJ Fb500 LBP	I Passed	
Tx DJ Fb500 LBP	Passed -	
Tx D COMINIT TransGapLeng	Passed 🖥	AV TO THE TOTAL PROPERTY OF THE TOTAL PROPER
Tx COMWAKE TransGapLength	Passed	
Tx UI During OOB	Passed	
Tx D COMINIT TransBurstL	Passed	
Tx COMWAKE TransBurstLen	Passed	[K
Tx Drive ResMaxInCOMRESET	Passed	
Tx Drive ResMinInCOMRESET	Passed	/ / I liku i / I
Tx Drive RejMaxOutCOMRESET	Passed	
Tx Drive RejMinOutCOMRESET		
Tx ResMaxInCOMWAKE	I Passed	
	Passed	
Tx ResMinInCOMWAKE	Passed	
Tx RejMaxOutCOMWAKE	Passed	
Tx RejMinOutCOMWAKE	Passed	
		ahead of Control of Co



SI Equipment List





Agilent vs. Tektronix

*Drive Master is positively necessary when RSG/RMT & OOB is tested with Agilent Solutions

when RSG/RWT & OOD is tested with Agricult sold					
Method Of Implementation	Tektronix 社	Agilent 社			
	PHY. TSG. And OOB Tests				
 ✓ PHY – Signal timing stability and SSC analysis ✓ TSG – Transmitter AC Parametric, Jitter, Amplitude ✓ OOB – Out Of Band signal validation 	 Real-Time Oscilloscope(DSA72004) Pulse Pattern Generator(AWG7102) 	 J-BERT(N4903A) Pulse Pattern Generator(81134A) Real-Time Oscilloscope(91304A) 			
	Rx/Tx Channel Tests				
 ✓ Rx/Tx – Device and Host electrical channel performance, impedance and return loss 	Sampling Scope + TDR Module(DSA8200)	• Sampling Scope + TDR Module (86100C)			
	SI Cable Tests				
 ✓ SI – Cable crosstalk, skew and frequency domain measurements, sdd21, sdd11 	Sampling Scope + TDR Module(DSA8200)	Sampling Scope + TDR Module (86100C)			
	RSG/RMT Tests				
 ✓ RSG/RMT – Receiver jitter and amplitude sensitivity compliance and margin test 	 Real-Time Oscilloscope(DSA72004) Pulse Pattern Generator(AWG7102) SATA BOX(C-H-S) Logic Analyzer(TLA7000 Series) 	J-BERT(N4903A)SATA BOX(N4219B)Logic Analyzer(16900 Series)			
	For Automation				
✓ Added Equipment	 RF Switch → Full Automation available BER can't measure 	 Full Automation not available (RF Switch has problems – occurrence of loss of signal integrity on Tx Test) 			

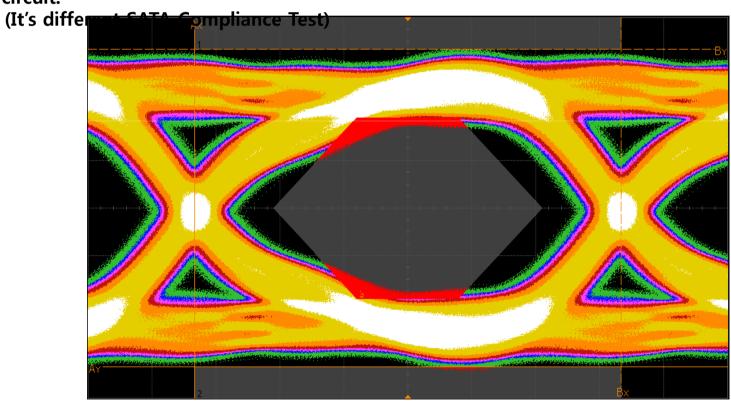
SI Test Result @ SSD Real Operation





Mask Test

- Using the SATA-II 3Gbps Mask, the Eye Opening Margin of Device is measured.
- Not only SATA PHY, Eye Diagram is measured on real operation that is all operating a surround circuit.





Signal Integrity On Real Operation

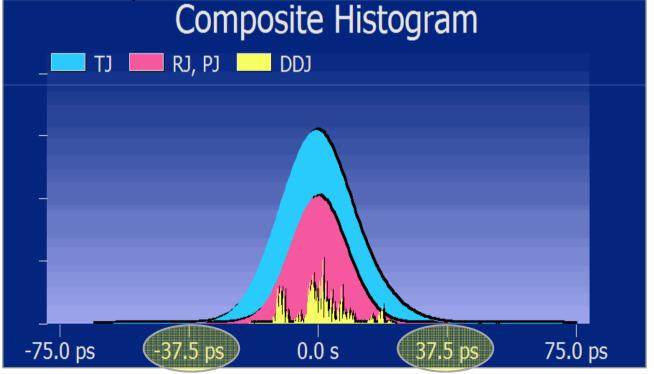


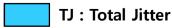


Jitter Test

- All jitter that inserted into the SSD is measured.
- Doing "write/read" a vulnerable pattern of SATA Interface that is captured jitter value

Not only SATA PHY, Jitter is measured on real operation that is all operating a surround circuit.
 (It's different SATA Compliance Test)





RJ: Random Jitter PJ: Periodic Jitter

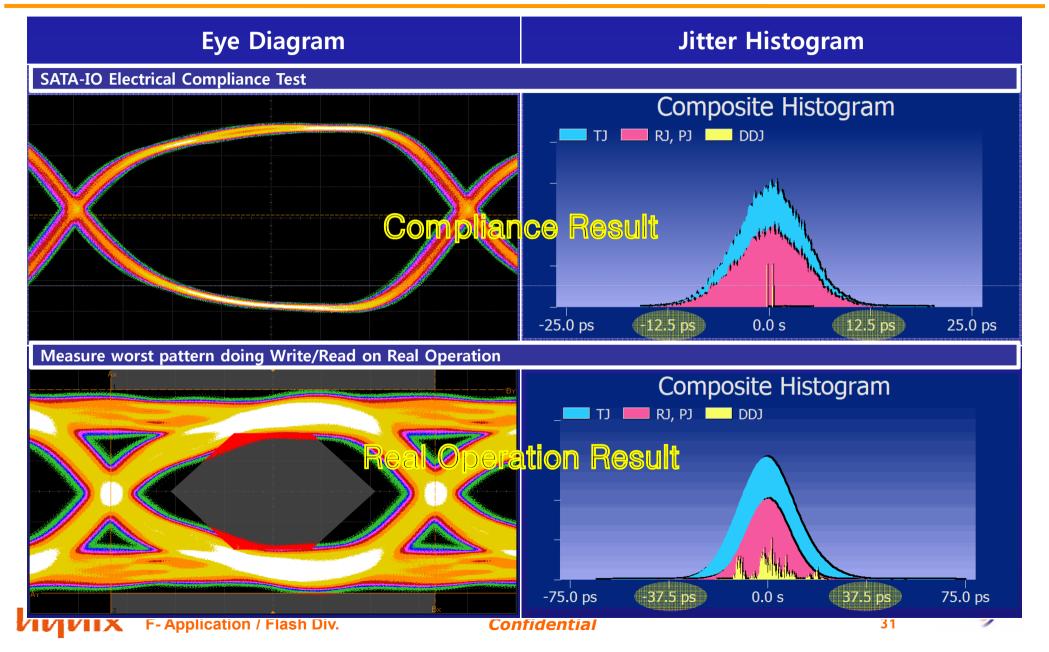




What is the different?







Standardization of SI On Real Operation





Standardization of SSD Signal Characteristics On Real Operation

 Various Character value is need to define comparing the real operation with the Compliance Test.

Standardization of Host Signal Characteristics On Real Operation

• Necessary, not only SSD but Host need to define the steady character value.

Development of Test Environment at Hardware and Software

- Now in used SATA Fixture it is impossible to signal capture during real operation.
- Software is need for CMD issue from Host to Device.



Signal Integrity Test Tool have to make base on Real Operation

→ Need to expedite to make the New SI Tool





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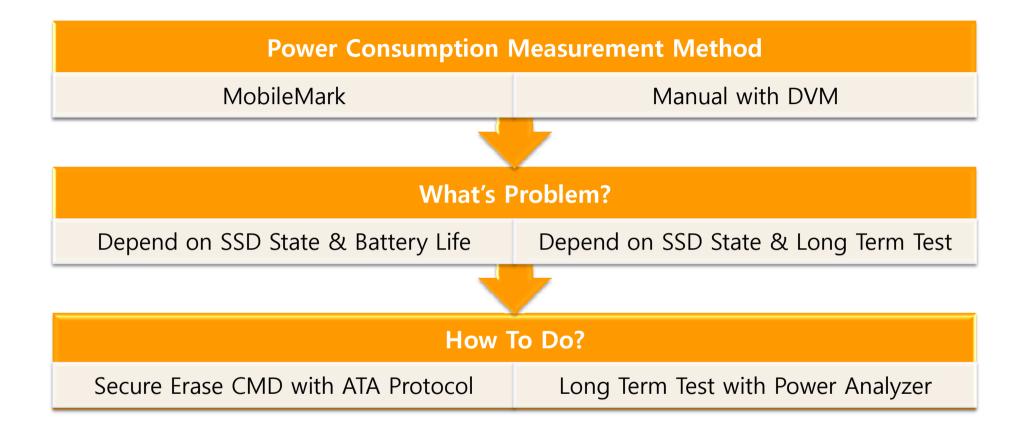
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Power Consumption







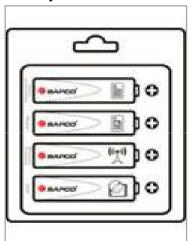


Power Consumption Measurement Method





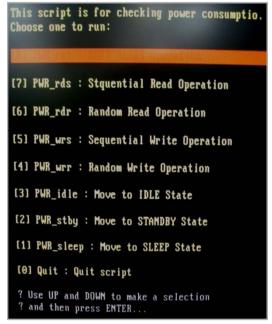
- MobileMark 2005 & 2007
- Major companies use to measure their Notebook Battery life
- A measurement tool of the Notebook Battery life by the General workloads



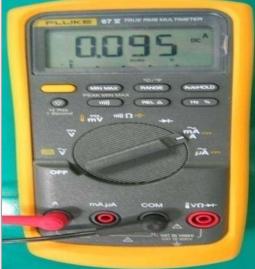




- Manual with DVM
- Sequential and Random Read/Write Operation measurement
- (Min. / Avg. / Max.) current value measures and compares with DVM









Mobile Mark Test Concept





System Requirements

	2005	2007	
CPU	 Intel® Pentium® III processor running at 300 MH z or equivalent 	 Intel® Pentium® M processor 1600 MHz or equivalent 	
Memory	• 256 MB	• 1 GB	
Display setting	• 1024x768, 16-bit color	• 1024 x 768, 16-bit color	
Operating System	• Microsoft Windows XP with Service Pack 2 These versions of Windows XP are supported: Chine se (Traditional) , Dutch, English, French, German, Ita lian, Japanese, Portuguese, Spanish	 Microsoft Windows XP with Service Pack 2 (32-bit and 64-bit) Microsoft Windows Vista (32-bit and 64-bit) MobileMark 2007 is supported only on English operating systems. 	
Hard drive space	• 3.0 GB free hard disk space	• 30 GB free hard disk space	
DVD-ROM drive	Available	Available	

Application

Applications	 Adobe® Photoshop® 6.0.1 InterVideo® WinDVD® 6.0 Macromedia® Flash 5.0 Microsoft® Internet Explorer Microsoft® Office® 2002 Netscape® Communicator® 6.01 Network Associates® McAfee® VirusScan® 5.13 WinZip Computing WinZip® 8.0 	 Adobe® AcrobatReader 7.0 Adobe® Illustrator® CS2 Adobe® Photoshop® CS2 Apple® Quicktime 7.1 Intervideo® WinDVD® 8 Macromedia® Flash 8 Microsoft® Office® 2003 Pro Microsoft® Project 2003 Winzip® 10.0
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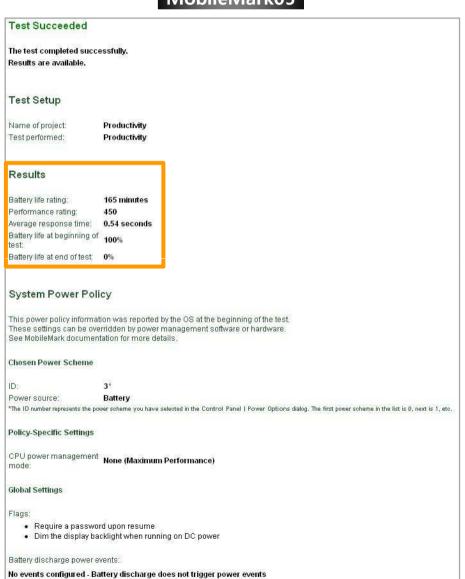


Test Result (MobileMark & DVM)





MobileMark05



Manual

Manual with DVM					
Seguential	Read	256Sectors (128KBytes)			
Sequential	Write	256Sectors (128KBytes)			
Random	Read	1Sector (512Bytes)			
Random	Write	1Sector (512Bytes)			

		Case 1	Case 2	Case 3
Booting		98	95	97
Base		98	95	97
	Idle	98	95	97
Power Mode	Standby	98	95	97
	Sleep	98	95	97
Sequen	Sequential Read		152	151
Sequential Write (Avg. / Max.)		290 / 311	313 / 329	306 / 318
Random Read		108	112	113
Random Write (Avg. / Max.)		180 / 201	211 / 225	205 / 247

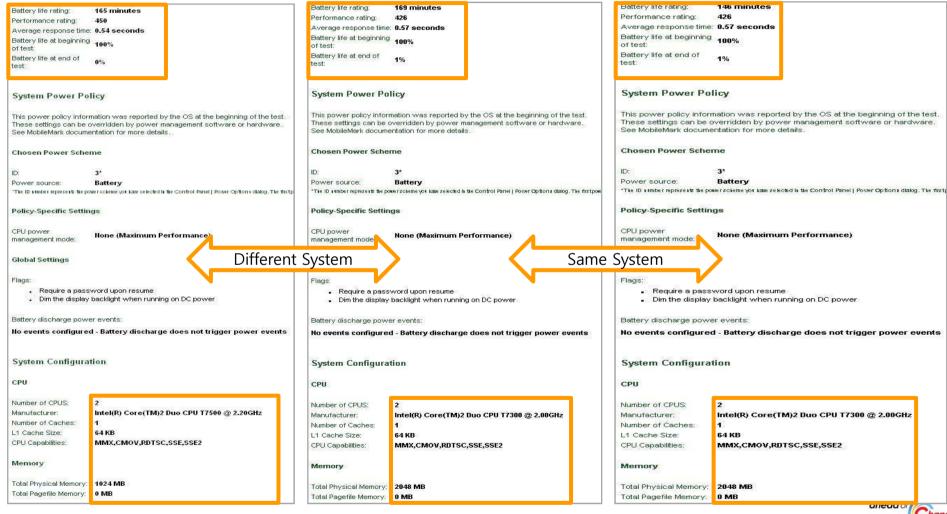


What's Problem?: MobileMark





- MobileMark measures battery life of the entire Notebook system.
- A kind of Notebook system, as well as the same Notebook system, has a different results.



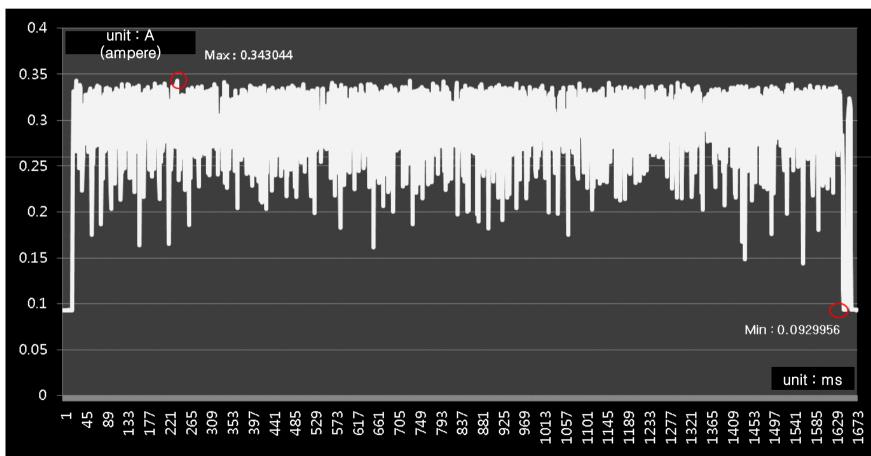
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What's Problem?: Manual vs DVM





- The measured values depend on the status of the device
- During a Dirty State operates Background Garbage Collection or Erase so it consumes more power than a Clean state
- Need to the Long Term (Clean State → Dirty State) measurement





Standardization of Power Measurement Tool





- I. Cann't believe the Mobile Mark & DVM Result
- II. In lack of consistency, test method difference, Need to make New tools & Please provide your ideas.

